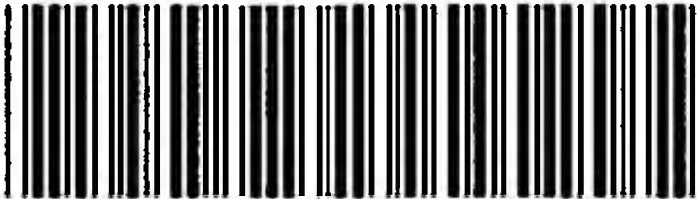


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/711,445	CHEN ET AL.	
	Examiner	Art Unit	
	David Goodwin	2818	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
438/164, 165, 197, 211, 257, 663, 264, 595, 594, 682, 695, 755, 770, 780	10/20/2005	DJG